

Measuring Magnetic $1/f$ Noise in Superconducting Microstructures and the Fluctuation-Dissipation Theorem

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Abstract.

The performance of superconducting devices like qubits, SQUIDs, and particle detectors is often limited by finite coherence times and $1/f$ noise. Various types of slow fluctuators in the Josephson junctions and the passive parts of these superconducting circuits can be the cause, and devices usually suffer from a combination of different noise sources, which are hard to disentangle and therefore hard to eliminate. One contribution is magnetic $1/f$ noise caused by fluctuating magnetic moments of magnetic impurities or dangling bonds in superconducting inductances, surface oxides, insulating oxide layers, and adsorbates. In an effort to further analyze such sources of noise, we have developed an experimental set-up to measure both the complex impedance of superconducting microstructures, and the overall noise picked up by these structures. This allows for important sanity checks by connecting both quantities via the fluctuation-dissipation theorem. Since these two measurements are sensitive to different types of noise, we are able to identify and quantify individual noise sources. The superconducting inductances under investigation form a Wheatstone-like bridge, read out by two independent cross-correlated dc-SQUID read-out chains. The resulting noise resolution lies beneath the quantum limit of the front-end SQUIDs and lets us measure noise caused by just a few ppm of impurities in close-by materials. We present measurements of the insulating SiO_2 layers of our devices, and magnetically doped noble metal layers in the vicinity of the pickup coils at $T = 40 \text{ mK} - 800 \text{ mK}$ and $f = 1 \text{ Hz} - 100 \text{ kHz}$.

Keywords: $1/f$ noise, superconducting microstructures, fluctuation-dissipation theorem

1. Introduction

Excess $1/f$ noise is a ubiquitous feature found in superconducting devices, often limiting their performance or application range. With recent progress in quantum computing [1, 2, 3], $1/f$ noise in superconducting quantum bits (qubits) [4] has been a particular focus of research. In charge qubits, for instance, it was found that such noise is caused by charged two-level fluctuators inducing charge fluctuations in the qubit [5, 6]. In devices with Josephson junctions, $1/f$ noise can be caused by fluctuations of the Josephson energy and the critical current originating from two-level fluctuators in the tunneling barrier [6, 7, 8]. Poorly understood, however, is excess low frequency magnetic flux noise, which can limit the coherence time of flux-, phase-, and transmon-type qubits and thus inhibit their scaling to more complex systems [9, 10, 11]. It is also present in superconducting quantum interference devices (SQUIDs) where it dominates at low frequencies [12], and in detectors such as metallic magnetic calorimeters (MMCs) [13].

Magnetic $1/f$ noise is characterized by a power spectral density of $S_\Phi(f) = A^2 (f/\text{Hz})^{-\alpha}$, with a largely device independent slope $\alpha \lesssim 1$ and an amplitude A in the order of a few $\mu\Phi_0/\sqrt{\text{Hz}}$, where $\Phi_0 = \frac{h}{2e}$ is the magnetic flux quantum. Its microscopic origin is not fully understood. In MMCs, $1/f$ noise scales with the amount of magnetic moments in the sensor material, suggesting that it originates from the paramagnetic, erbium-doped gold or silver sensor [14]. For SQUIDs, flux, and phase qubits, different models consider magnetic flux noise from the stochastic hopping of electrons [15], paramagnetic dangling bonds [16], strongly interacting surface spins [17, 18], metal-induced gap states [19, 20], or adsorbed O_2 molecules [21, 22]. Both the experimental verification of theories and the reduction of noise in specific set-ups can be difficult, since devices usually suffer from a combination of different noise sources, which are hard to disentangle and therefore hard to eliminate.

We have taken this problem as motivation and have developed a device to measure magnetic flux noise of superconducting circuits, with the focus lying on isolating individual noise sources. The general idea is to combine two different methods of measuring noise in the same device: First, a direct measurement of noise via a pair of two-stage dc-SQUID read-out chains, which are cross-correlated in order to reduce read-out noise. This will give us a measure of the sum of all noise originating from the superconducting circuit. Second, a measurement of the complex susceptibility of inductances in close proximity to a sample material. By applying the fluctuation-dissipation theorem, we then calculate the magnetic flux noise caused by the sample. A comparison of results from the two measurement modes tells us which noise components originate from the sample material and which from other parts of the system.

In the following, we present our experimental set-up, including a detailed explanation of the two measurement modes. There follows measurements of a highly paramagnetic sample material with a known amount of localized magnetic moments, as well as sputtered SiO_2 , an insulator commonly used in superconducting microstructures.

2. Experimental Methods

Figure 1 shows a sketch of the set-up. The central part is a Wheatstone-like bridge consisting of four almost identical, superconducting, microstructured, meander-shaped coils placed on a $3\text{ mm} \times 3\text{ mm}$ silicon chip. Each meander consists of 50 lines with a width of $5\text{ }\mu\text{m}$ and a pitch of $10\text{ }\mu\text{m}$, resulting in an inductance of $L_0 = 7\text{ nH}$. Two opposite meander coils are coated with the sample material (orange), changing their inductance to $L = L_0(1 + \chi F)$, where χ is the magnetic susceptibility of the sample material, and F is the filling factor. The sample is galvanically decoupled from the coils by a thin layer of SiO_2 covering the entire chip. Further components connected to the main chip allow us to read out the generated noise in two different measurement modes.

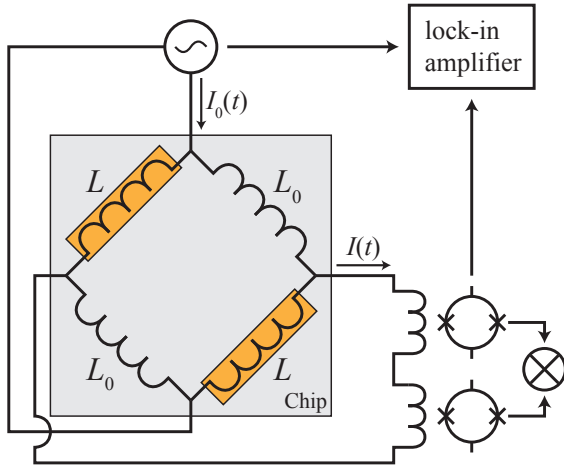


Figure 1: Circuit diagram of the set-up with sample material (orange) placed on opposite inductors. Noise can be read out directly using a pair of cross-correlated two-stage dc-SQUID read-out chains. Alternatively, we can measure the susceptibility of the sample material by applying an AC signal $I_0(t)$ and determining the amplitude and phase shift of the current $I(t)$ using a lock-in amplifier.

2.1. Cross-correlated noise read-out

In cross-correlation mode, we read out the noise $a(t)$ of the superconducting microstructure via a pair of two-stage dc-SQUID read-out chains, where the input coils of the two chains are connected in series (see figure 1). From the read-out chains originate additional undesired noise contributions $n_1(t)$ and $n_2(t)$. In a realistic experimental setting, there is a finite amount of cross-talk between the read-out chains. We model this cross-talk from the respective other channel as a contribution with relative fraction δ . As a result, the actually measured time traces $s_1(t)$ and $s_2(t)$ are

$$\begin{aligned} s_1(t) &= (1 - \delta) \cdot (a(t) + n_1(t)) + \delta \cdot (a(t) + n_2(t)) \quad \text{and} \\ s_2(t) &= (1 - \delta) \cdot (a(t) + n_2(t)) + \delta \cdot (a(t) + n_1(t)) \quad . \end{aligned} \tag{1}$$

Solving the system of equations results in the time traces

$$\begin{aligned} u(t) &= a(t) + n_1(t) = \frac{s_1(t) - \delta(s_1(t) + s_2(t))}{1 - 2\delta} \quad \text{and} \\ v(t) &= a(t) + n_2(t) = \frac{s_2(t) - \delta(s_1(t) + s_2(t))}{1 - 2\delta} \quad , \end{aligned} \tag{2}$$

which have reduced cross-talk. As a next step, we cross-correlate these two time traces [23]. The cross-correlated power spectral density $S_{uv}(f)$ is defined as the real part $\text{Re} \{ \}$

of the Fourier transform \mathcal{F} of the cross-correlation function

$$\begin{aligned} R_{uv}(\tau) &= \mathbb{E}[u(t)v(t-\tau)] \\ &= \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-T/2}^{T/2} u(t)v(t-\tau)dt \\ &= \lim_{T \rightarrow \infty} \frac{1}{T} \int_{-\infty}^{\infty} u_T(t)v_T(t-\tau)dt \quad . \end{aligned} \quad (3)$$

Here, $\mathbb{E}[\]$ is the expectation value and the subscript T represents a truncation to the measurement time T . Using the convolution theorem, we find

$$S_{uv}(f) = \text{Re} \{ \mathcal{F}[R_{uv}(\tau)] \} = \lim_{T \rightarrow \infty} \frac{1}{T} \text{Re} \{ \mathcal{F}^*[u_T(t)](f) \mathcal{F}[v_T(t)](f) \} \quad , \quad (4)$$

where the asterisk denotes the complex conjugate. In order to simplify notation, we introduce the Fourier transform $X = \mathcal{F}[x_T(t)]$ of a time trace $x(t)$ truncated to T . In an experimental setting where we average over N measurements, each with a finite measurement time T , the averaged cross-correlated power spectral density then is

$$\begin{aligned} \langle S_{uv} \rangle_N &= \frac{1}{T} \text{Re} \{ \langle U^* V \rangle_N \} \\ &= \frac{1}{T} \text{Re} \{ \langle (A^* + N_1^*)(A + N_2) \rangle_N \} \\ &= \frac{1}{T} \text{Re} \{ \langle A^* A \rangle_N + \langle A^* N_2 \rangle_N + \langle N_1^* A \rangle_N + \langle N_1^* N_2 \rangle_N \} \\ &= \frac{1}{T} \text{Re} \left\{ \langle A^* A \rangle_N + \mathcal{O}(1/\sqrt{N}) \right\} \quad . \end{aligned} \quad (5)$$

For sufficiently large N , the statistically independent terms vanish and we are left with the cross-talk corrected power spectral density $S_a = \frac{1}{T} \text{Re} \{ \langle A^* A \rangle_N \}$ of only the noise in our superconducting microstructure. Note that while read-out noise n_1 and n_2 is removed, S_a might still have contributions other than the magnetic flux noise caused by the sample material, such as Johnson noise or magnetic flux noise originating from other sources within the input circuit.

We demonstrate this process on data taken from noise measurements of an SiO₂ sample with an unknown amount of magnetic impurities. Data of the two individual channels appear in green in figure 2. At high frequencies, the spectra are dominated by the well understood white SQUID noise [24] with an amplitude of $\sqrt{S_{s,w}} = 0.29 \mu\Phi_0/\sqrt{\text{Hz}}$. This corresponds to an energy sensitivity $\epsilon_s = \frac{S_\Phi}{2L_s}$ of the SQUID of around $28\hbar$, where we estimate the SQUID inductance to be $L_s = 60 \text{ pH}$. At low frequencies, we observe $1/f$ flux noise $S_{\Phi_s}(f) = S_{\Phi_s}(1 \text{ Hz}) (f/\text{Hz})^{-\alpha}$ with $\sqrt{S_{\Phi_s}(1 \text{ Hz})} = 5.5 \mu\Phi_0/\sqrt{\text{Hz}}$ and $\alpha = 0.75$. Both components are significantly reduced after cross-correlation (red), and the underlying noise spectrum of the input circuit and Wheatstone bridge becomes visible. Based on the circuit design, we find that the cross-talk must be negative and at most 2%. We thus choose a value of $\delta = (-1 \pm 1)\%$ (blue). Since $\delta < 0$, the noise level increases, but the data nevertheless approach the quantum

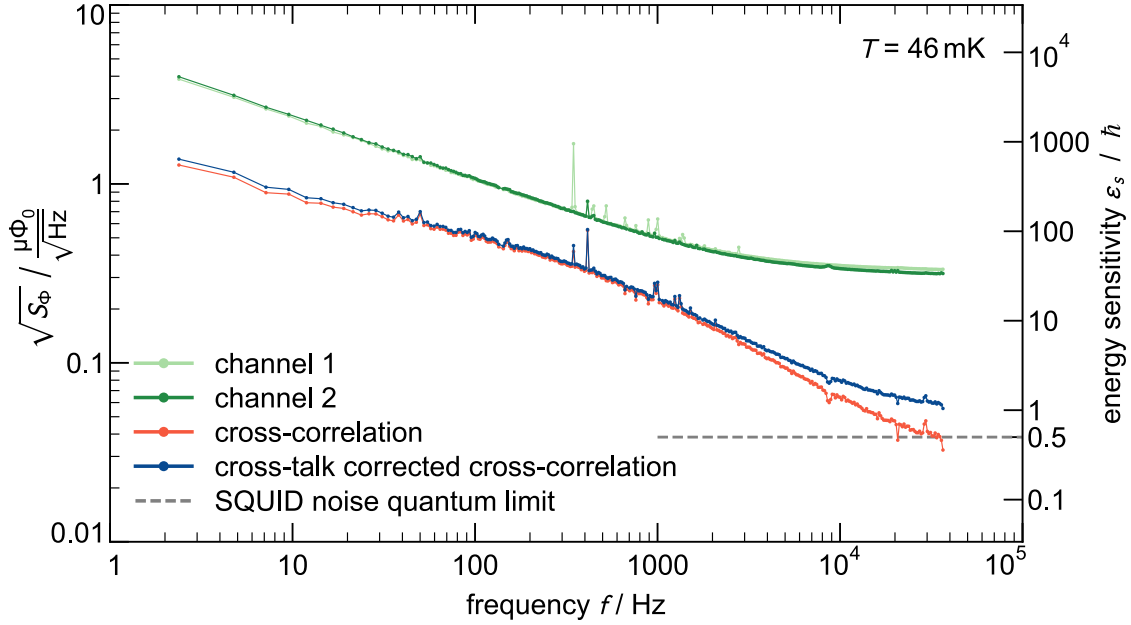


Figure 2: Noise spectra of an SiO_2 sample taken in cross-correlation mode. Data from a single channel appears in green, cross-correlated data in red, and data after cross-talk correction in blue. Via the cross-correlation, SQUID read-out noise is greatly reduced. Since cross-talk is negative, correcting for it increases the noise level.

noise limit $\epsilon_s \gtrsim \hbar/2$ of a single SQUID at $T = 0$ K [25]. The uncertainty in the cross-talk can result in a systematic error at low noise levels, but the amount of cross-talk between channels can be further reduced by increasing L_0 . To understand this, consider a magnetic flux change $\partial\Phi_m$ in one of the meander coils due to magnetic flux noise of the sample. It is proportional to L_0 , assuming the increase in L_0 is achieved through an increase in the meander footprint and thus also in area covered by the sample. Using Kirchhoff's rules and approximating $L \approx L_0$, we find that for our circuit, $\partial\Phi_m$ creates a flux change

$$\partial\Phi_{s,m} = \frac{k\sqrt{L_i L_s}}{2(L_0 + 2(L_i + L_w))} \partial\Phi_m \quad (6)$$

in one of the front-end SQUIDS [26]. Here, k is the dimensionless coupling constant between SQUID input coil L_i and the inductance L_s of the front-end SQUID, and L_w is the inductance of the aluminum bond wires connecting the Wheatstone bridge with the input coils of the SQUID. At the same time, back-action flux $\partial\Phi_x$ induced in the input coil by one of the SQUIDS leads to cross-talk

$$\partial\Phi_{s,x} = \frac{k\sqrt{L_i L_s}}{L_0 + 2(L_i + L_w)} \partial\Phi_x \quad (7)$$

in the other SQUID. Importantly, $\partial\Phi_x$ is dominated by read-out noise and thus independent of L_0 to first order. As a result, $\partial\Phi_{s,x}$ vanishes for large L_0 , while $\partial\Phi_{s,m}$

stays constant and we find

$$\frac{\partial \Phi_{s,m}}{\partial \Phi_{s,x}} \propto L_0 \quad . \quad (8)$$

Instead, for experiments where a large L_0 is impossible and noise from a fixed $L_0 \ll L_i$ should be measured, it is best to connect the two SQUID input coils in parallel. For that geometry, we find

$$\begin{aligned} \partial \Phi_{s,m,\text{par}} &= \frac{k\sqrt{L_i L_s}}{2(2L_0 + (L_i + L_w))} \partial \Phi_m \gg \partial \Phi_{s,m} \quad \text{and} \\ \partial \Phi_{s,x,\text{par}} &= \frac{k\sqrt{L_i L_s}}{\frac{(L_i + L_w)^2}{L_0} + 2(L_i + L_w)} \partial \Phi_x \ll \partial \Phi_{s,x} \quad . \end{aligned} \quad (9)$$

2.2. Noise read-out via susceptibility

Our device allows for a second measurement mode, where we operate it as a Wheatstone-like bridge by applying an AC signal $I_0(f, t) = \hat{I}_0 \sin(2\pi f t)$ over one diagonal and measuring the current $I(f, t) = \hat{I} \sin(2\pi f t - \theta)$ flowing across the other diagonal via one of the dc-SQUIDS. A lock-in amplifier provides a precise measurement of the relative amplitude \hat{I}/\hat{I}_0 and the phase shift θ of the signal. The latter is caused in part by finite signal transmission speed, which we must correct for, and in part by magnetic moments in the sample material not following the magnetic field caused by I_0 instantaneously - a fact we express by attributing the sample material a complex magnetic susceptibility $\chi = \chi' + i\chi''$. Using Kirchhoff's rules, we find the relation

$$I(f, t) = I_0(f, t) \frac{L - L_0}{2 L_{\text{tot}}} = I_0(f, t) \frac{L_0}{2 L_{\text{tot}}} (\chi' F + i\chi'' F) \quad , \quad (10)$$

where $L_{\text{tot}} = L_b + 2(L_i + L_w)$ is the total inductance of the circuit, containing the inductance $L_b = \frac{1}{2}(L_0 + L)$ of the Wheatstone bridge. It follows that

$$\chi' F = \frac{2 L_{\text{tot}}}{L_0} \frac{\hat{I}}{\hat{I}_0} \cos(\theta) \quad \text{and} \quad \chi'' F = \frac{2 L_{\text{tot}}}{L_0} \frac{\hat{I}}{\hat{I}_0} \sin(\theta) \quad . \quad (11)$$

When measuring paramagnetic samples, $\chi' F$ should vanish in the limit of low frequencies and high temperatures. In practice, however, this is not the case, since the four coils of the Wheatstone bridge have slightly different inductances due to fabrication inaccuracies. In our model we account for this by replacing one of the base inductors L_0 with a slightly altered inductor $L_{0,a}$. During data evaluation, we then determine $L_{0,a}$ by extrapolating data to $1/T \rightarrow 0$ using Curie's law and then choosing $L_{0,a}$ so that $\chi' F(f \rightarrow 0, 1/T \rightarrow 0) = 0$. Measurements of three different devices resulted in asymmetries $|L_0 - L_{0,a}|/L_0$ of less than 0.3 %.

Consider now the imaginary part of the susceptibility. Any non-zero value for χ'' leads to a dissipative component $\text{Re}(Z_b)$ of the Wheatstone bridge's impedance

$$\begin{aligned} \text{Re}(Z_b) &= \text{Re}(i 2\pi f L_b) = \text{Re}(i \pi f (L_0 + L)) \\ &= \text{Re}(i \pi f (2L_0 + L_0(\chi' + i\chi'')F)) = -\pi f L_0 \chi'' F \quad , \end{aligned} \quad (12)$$

which is positive, since $\chi'' < 0$. According to the fluctuation-dissipation theorem, we expect a corresponding voltage noise $S_U(f) = 4k_B T \text{Re}(Z_W)$ across the impedance $Z_{\text{tot}} = i 2\pi f L_{\text{tot}}$ of the circuit, resulting in flux noise

$$\sqrt{S_\Phi(f)} = k \sqrt{L_i L_s} \frac{\sqrt{S_U(f)}}{|Z_{\text{tot}}|} = \frac{k \sqrt{L_i L_s}}{L_{\text{tot}}} \sqrt{\frac{k_B T L_0 |\chi''| F}{\pi f}} \quad (13)$$

in the SQUID. Note that in contrast to noise read out in cross-correlation mode, only asymmetrically distributed magnetic flux noise sources are probed by measuring χ'' .

3. Results and Discussion

3.1. Measurement mode comparison

As a first demonstration of the functionality of our device, we present measurements from a chip onto which we deposited a $2.58 \mu\text{m}$ thick Au:Er film with an atomic erbium concentration of $x_{\text{Er}} = (2480 \pm 20)$ ppm. The localized 4f electrons of the erbium have an effective spin $\tilde{S} = 1/2$ and an effective $\tilde{g} = 6.8$, with the gold acting as a passive dilutant to prevent magnetic ordering [27]. This results in a system of mostly free magnetic moments, leading to a strongly paramagnetic material with a Curie-Weiss-type temperature dependence of χ' [28]. Data using both measurement modes appear in orange in figure 3. To first order, the noise is independent of measurement mode, which tells us that almost all of the noise in the superconducting circuit consists of magnetic flux noise caused by the sample. Given the magnetic nature of the erbium, this is not surprising. We describe the noise as a $1/f$ -type noise $S_{\Phi, \text{Er}}(f) = S_{\Phi, \text{Er}}(1 \text{ Hz}) (f/\text{Hz})^{-\alpha}$ with $S_{\Phi, \text{Er}}(1 \text{ Hz}) = (13.1 \mu\Phi_0/\sqrt{\text{Hz}})^2$ and $\alpha = 1.00 \pm 0.03$. Using finite element simulations of the magnetic field distribution in the material, we are able to assign a value of $S_{\text{Er}}(1 \text{ Hz}) = (0.115 \pm 0.006) \mu_B^2/\text{Hz}$ per erbium atom [13]. Our result is compatible with noise that was previously observed in MMCs containing erbium alloys, where a value of $\sim 0.1 \mu_B^2/\text{Hz}$ per erbium atom was estimated with larger uncertainties [14].

On a second device we deposited a 440 nm thick layer of SiO_2 over the entire device, with two square holes in the SiO_2 over opposite meanders giving us the required asymmetry. The magnetic flux noise measured using susceptibility mode appears as blue squares in figure 3. It has a slightly frequency dependent slope of about $f^{-0.9}$ and with $S_{\Phi, \text{SiO}_2}(1 \text{ Hz}) = (1.65 \mu\Phi_0/\sqrt{\text{Hz}})^2$, it lies significantly below the total noise of the circuit, as measured in cross-correlation mode (blue dots). Other noise components are dominant in this set-up, which we analyze in section 3.2. Comparing the magnetic flux noise of both samples, we estimate that roughly 60 ppm of impurities are magnetically active at 1 Hz, assuming that the impurities in SiO_2 have a similar magnetic moment to erbium. More likely, however, is that we are mostly measuring dangling bonds with a spin of $1/2$ and a g -factor of 2 with an appropriately scaled concentration of around 200 ppm. From calibration measurements, we determine that this value lies around a factor of three above the resolution limit of susceptibility mode.

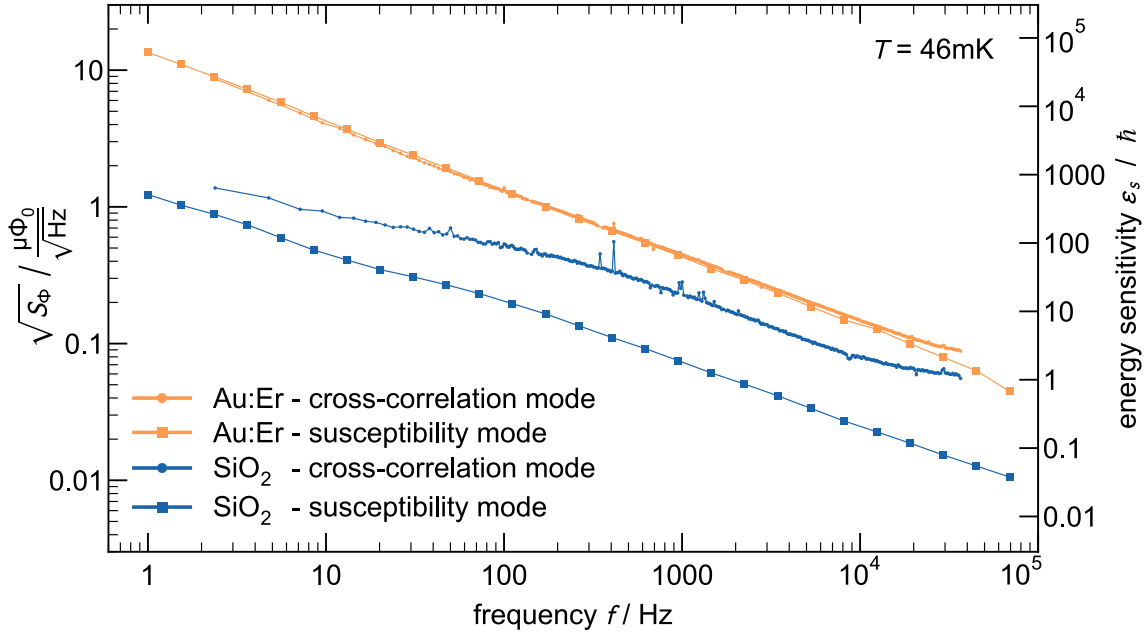


Figure 3: Results of noise measurements on gold doped with 2480 ppm erbium (orange), and on SiO_2 with unknown magnetic impurities (blue) at $T = 46 \text{ mK}$. Data from susceptibility mode (squares) represents only the magnetic flux noise caused by the respective sample, while data from cross-correlation mode (circles) includes additional components from Johnson noise, white noise, and other $1/f$ noise.

3.2. Temperature dependence

We gain further insight into the origin of different noise sources by repeating the above measurement at different temperatures. Cross-correlated data of SiO_2 appears in figure 4a for temperatures between 46 mK and 800 mK.

We observe a general temperature dependence of the form $\sqrt{S} \propto \sqrt{T}$ over large parts of the spectrum, which we describe with the fit

$$\sqrt{S_{\Phi, \text{fit}}(f, T)} = \sqrt{S_J \frac{T}{1 \text{ K}} \left(1 + \frac{2f}{\pi f_c}\right)^{-\alpha} + S_{1/f}/f} \quad , \quad (14)$$

which appears in gray in figure 4 and matches data well for all but the highest frequencies. The fit function consists of two parts: First, a component with amplitude $S_J = (2.9 \mu\Phi_0/\sqrt{\text{Hz}})^2$, which we attribute to thermal motion of electrons (Johnson noise) in the copper experimental platform coupling magnetically into the loop formed by the bond wires between our device and the front-end SQUIDs. Due to the skin effect, there is a low-pass behavior with $f_c = 143 \text{ Hz}$ and $\alpha = 1.19$. Such magnetic Johnson noise has been previously observed in similar set-ups [29]. The second part is a $1/f$ component with $S_{1/f} = (2.16 \mu\Phi_0/\sqrt{\text{Hz}})^2$, which is caused at least in part by magnetic flux noise from the SiO_2 , as measurements in figure 3 show. Note that the susceptibility mode

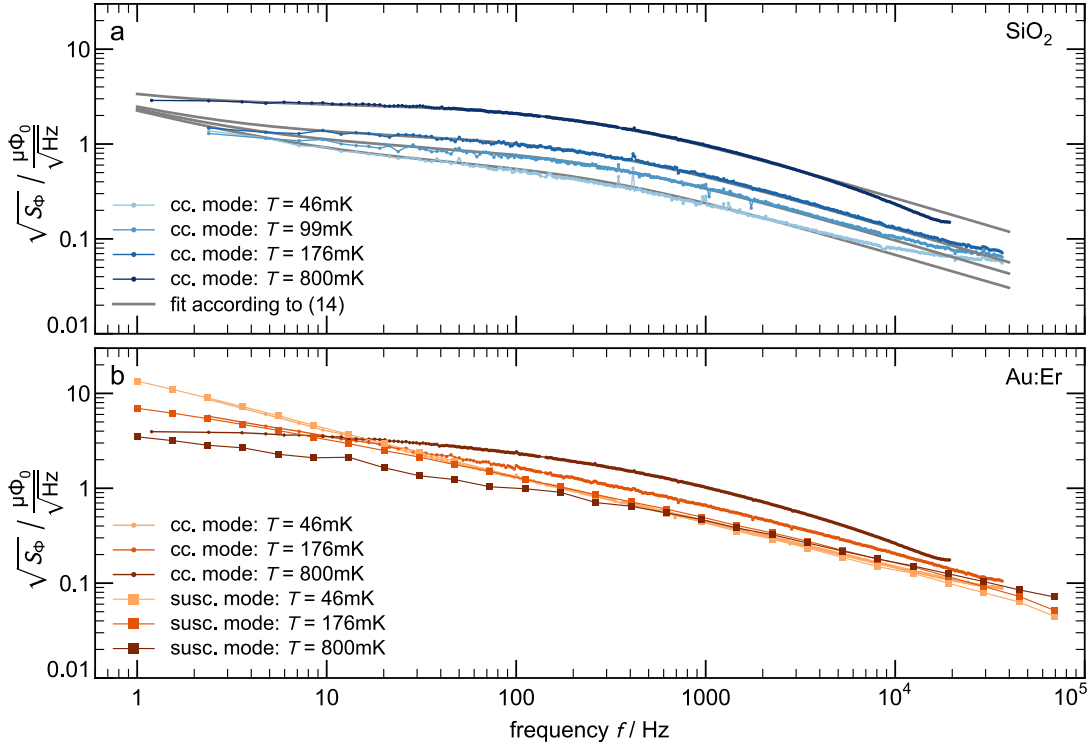


Figure 4: **a)** Data from noise measurements of SiO_2 in cross-correlation mode at different temperatures. A fit given by (14), which is based on a combination of magnetic Josephson noise and a $1/f$ component, matches data well. **b)** Temperature dependent noise of Au:Er for both measurement modes. Johnson noise also affects cross-correlated data at highest temperatures, while the magnetic flux noise is largely temperature independent.

measurement in figure 3 is based on holes in the SiO_2 layer, so only noise caused by these asymmetric sections is measured. In cross-correlation mode, however, magnetic flux noise from SiO_2 on other parts of the chip can also contribute, such as the lines leading to the bond pads, or even from SiO_2 on the front-end SQUID chips. As a result, we are not surprised that the $1/f$ component from cross-correlation mode lies above the noise measured using susceptibility mode.

Data of the Au:Er sample appear in figure 4b for both measurement modes. The magnetic flux noise (squares) is largely temperature independent, which matches previous observations [14]. At highest temperatures, however, we observe reduced noise at low frequencies, since the variable inductance of the aluminum bond wires near T_c influences the measurement. Data from cross-correlation mode show an additional component at high temperatures and medium frequencies, which is well described by equation (14). This points toward that noise component being sample independent and originating from the experimental set-up, reaffirming the assumption that the source is magnetic Johnson noise.

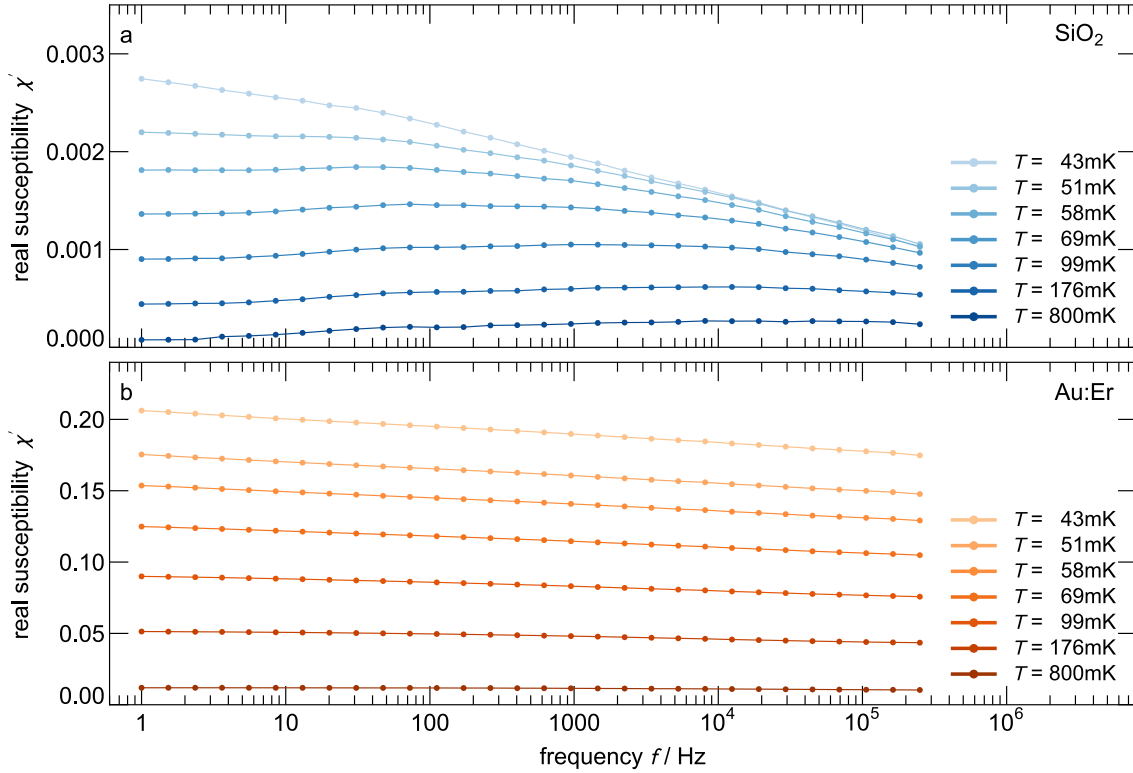


Figure 5: Data of the real part of the AC susceptibility appears as a function of frequency and temperature for SiO_2 (a) and Au:Er (b). For individual frequencies, a Curie-Weiss law describes data well, while for individual temperatures a frequency dependence is visible.

3.3. Susceptibility measurements

Besides extracting the magnetic flux noise from χ'' via the fluctuation-dissipation theorem, we can also gain insight on the dynamics of magnetic moments in the sample material from the real part χ' of the complex AC susceptibility. Figure 5 shows the frequency dependence of the corresponding data for SiO_2 (a) and Au:Er (b). When considering data for either sample at a fixed frequency, χ' increases towards lower temperatures and saturates in a Curie-Weiss like fashion, as is expected for paramagnetic samples. For fixed temperatures, we observe a general trend of decreasing susceptibility with increasing frequency. To understand this, we model each magnetic moment μ_i as a Debye relaxator with a relaxation time τ_i , so that at an angular frequency ω , it contributes with a fraction $(1 + (\omega\tau_i)^2)^{-1}$ of its magnetic moment to χ' . Averaging over many relaxators with different relaxation times thus yields different shapes for the averaged $\chi'(f)$ curve, depending on the distribution of relaxation times. In our case, for instance, we note that as the frequency increases, $\chi'(f)$ drops quickly for the glassy SiO_2 in which slow phononic relaxation with a long τ_i dominates. In Au:Er , with fast electron-spin relaxation times, magnetic moments can have shorter relaxation times

and the frequency dependence of the susceptibility is smaller. In fact, Au:Er data for $T \leq 69$ mK are well described by $\chi' \propto -\log(f)$, telling us that relaxation times must be spaced logarithmically. Using

$$\chi'' = \frac{\pi}{2} \frac{\partial \chi'}{\partial \ln f} \quad (15)$$

derived for spin-glass systems with their broad distribution of relaxation times [30], we get a frequency independent loss χ'' and via the fluctuation-dissipation theorem once again the $1/f$ noise presented above. Calculating noise in this way is consistent with the direct calculation via the phase shift of the AC signal, but has larger uncertainties. It does show, however, that (15) is applicable for our Au:Er sample, which is remarkable, since we expect the spin-glass transition temperature of our sample to lie in the low mK range [13]. A broad distribution of relaxation times in Au:Er could originate from the complex magnetic nature of the material, which includes RKKY and dipole-dipole interactions between erbium ions, as well as crystal field effects from the gold lattice [28]. Simulations of magnetically similar Ag:Er alloys have shown that these interactions can lead to a wide range of energy level spacing, with individual pairs or clusters of erbium atoms having energy gaps of well above $100 \text{ mK} \cdot k_B$ [31].

4. Conclusion

We have presented a novel device which allows us to analyze noise sources in superconducting microstructures. By combining cross-correlated read-out and AC susceptibility measurements, we are able to distinguish and quantify SQUID noise, magnetic Johnson noise, and magnetic $1/f$ noise. Our device is thus a tool to map out potential noise sources in an experimental set-up before performing the actual experiment. This may be applied to a wide range of superconducting microstructures. Thinkable, for instance, is replacing the meander-shaped coils with SQUIDs or qubits, in order to measure the magnetic flux of an entire device.

Besides disentangling noise sources in an experimental set-up, we are also able to analyze the magnetic nature of sample materials. In measurements on Au:Er, we find a nearly temperature independent $1/f^\alpha$ magnetic flux noise component with an amplitude of $S_{\text{Er}}(1 \text{ Hz}) = 0.115 \mu_B^2/\text{Hz}$ per erbium ion and $\alpha = 1.00$. We are able to measure noise beneath the quantum limit, enabling us to quantify the $1/f$ noise of weakly magnetic SiO_2 . By combining these results with measurements of the temperature and frequency dependence of the real part of our samples' susceptibility, we obtain a detailed picture of the dynamics of the magnetic moments.

5. Data Availability

The datasets generated during and/or analyzed during the current study are available in the Zenodo repository doi.org/10.5281/zenodo.7993965.

6. Conflict of Interest

The authors declare that they have no conflict of interest.

7. Acknowledgements

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